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August 2015

## FDMS8095AC

# **Dual N & P-Channel PowerTrench® MOSFET**

N-Channel: 150 V, 27 A, 30 m $\Omega$  P-Channel: -150 V, -2.2 A, 1200 m $\Omega$ 

#### **Features**

Q1: N-Channel

■ Max  $r_{DS(on)}$  = 30 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 6.2 A

■ Max  $r_{DS(on)}$  = 41 m $\Omega$  at  $V_{GS}$  = 6 V,  $I_D$  = 5.2 A

Q2: P-Channel

■ Max  $r_{DS(on)}$  = 1200 m $\Omega$  at  $V_{GS}$  = -10 V,  $I_D$  = -1 A

■ Max  $r_{DS(on)}$  = 1400 m $\Omega$  at  $V_{GS}$  = -6 V,  $I_D$  = -0.9 A

■ Optimised for active clamp forward converters

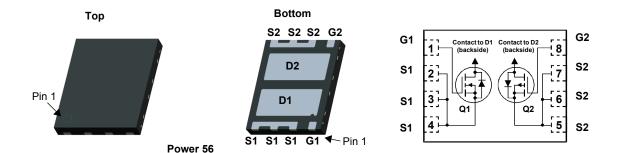
■ RoHS Compliant

#### **General Description**

These dual N and P-Channel enhancement mode Power MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance. Shrinking the area needed for implementation of active clamp topology; enabling best in class power density.

#### **Applications**

- DC-DC Converter
- Active Clamp



## MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Paramete	Parameter				Units
$V_{DS}$	Drain to Source Voltage			150	-150	V
$V_{GS}$	Gate to Source Voltage			±20	±25	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C	(Note 5)	27	-2.2	
	Drain Current -Continuous	T <sub>C</sub> = 100 °C	(Note 5)	17	-1.4	^
ID	-Continuous	T <sub>A</sub> = 25 °C		6.2 <sup>1a</sup>	-1 <sup>1b</sup>	Α
	-Pulsed		(Note 4)	143	-8.8	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	216	6	mJ
	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C		2.3 <sup>1a</sup>	2.3 <sup>1b</sup>	
$P_{D}$	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C		0.9 <sup>1c</sup>	0.9 <sup>1d</sup>	W
	Power Dissipation for Single Operation	T <sub>C</sub> = 25 °C		50	12.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperatur	Operating and Storage Junction Temperature Range			+150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	55 <sup>1a</sup>	55 <sup>1b</sup>	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	138 <sup>1c</sup>	138 <sup>1d</sup>	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.5	10	

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8095AC	FDMS8095AC	Power 56	13"	12 mm	3000 units

## **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Chara	octeristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D$ = 250 $\mu$ A, $V_{GS}$ = 0 $V$ $I_D$ = -250 $\mu$ A, $V_{GS}$ = 0 $V$	Q1 Q2	150 -150			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C $I_D$ = -250 μA, referenced to 25 °C	Q1 Q2		103 122		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 120 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = -120 V, V <sub>GS</sub> = 0 V	Q1 Q2			1 -1	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V	Q1 Q2			±100 ±100	nA nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = -250 \mu A$	Q1 Q2	2.0 -2.0	3.2 -3.2	4.0 -4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$ , referenced to 25 °C $I_D = -250 \mu A$ , referenced to 25 °C	Q1 Q2		-11 -6		mV/°C
_		$V_{GS} = 10 \text{ V}, I_D = 6.2 \text{ A}$ $V_{GS} = 6 \text{ V}, I_D = 5.2 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 6.2 \text{ A}, T_J = 125 °C$	Q1		25 33 48	30 41 58	<b></b> 0
r <sub>DS(on)</sub> Static Drain	Static Drain to Source On Resistance	$V_{GS}$ = -10 V, $I_{D}$ = -1 A $V_{GS}$ = -6 V, $I_{D}$ = -0.9 A $V_{GS}$ = -10 V, $I_{D}$ = -1 A, $T_{J}$ = 125 °C	Q2		840 940 1520	1200 1400 2171	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DD} = 10 \text{ V}, I_D = 6.2 \text{ A}$ $V_{DD} = -10 \text{ V}, I_D = -1 \text{ A}$	Q1 Q2		19 0.75		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	Q1 V <sub>DS</sub> = 75 V, V <sub>GS</sub> = 0 V, f = 1 MHZ	Q1 Q2		1441 162	2020 230	pF
C <sub>oss</sub>	Output Capacitance	Q2	Q1 Q2		127 13	180 25	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{DS} = -75 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2		4.4 0.6	10 5	pF
R <sub>g</sub>	Gate Resistance		Q1 Q2	0.1 0.1	1.3 3.3	3.3 8.3	Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	Q1	Q1 Q2	12 5.2	22 11	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 75 \text{ V, } I_{D} = 6.2 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6 \Omega$	Q1 Q2	2.7 1.6	10 10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	Q2 V <sub>DD</sub> = -75 V, I <sub>D</sub> = -1 A,	Q1 Q2	18 7.4	33 15	ns
t <sub>f</sub>	Fall Time	$V_{GS} = -10 \text{ V, } R_{GEN} = 6 \Omega$	Q1 Q2	4 6.3	10 13	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to } 10 \text{ V}$ $V_{GS} = 0 \text{ V to } -10 \text{ V}$ $V_{GS} = 0 \text{ V to } 6 \text{ V}$ $V_{DD} = 75 \text{ V}$ , $I_{D} = 6.2 \text{ A}$	Q1 Q2	21 2.8	30 4	nC
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to 6 V} $ $V_{GS} = 0 \text{ V to -6 V} $ $I_D = 6.2 \text{ A}$	Q1 Q2	13 1.8	19 2.6	nC
Q <sub>gs</sub>	Gate to Source Charge	Q2	Q1 Q2	6.7 0.8		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>DD</sub> = -75 V I <sub>D</sub> = -1 A	Q1 Q2	3.9 0.7		nC

## Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

**Parameter** 

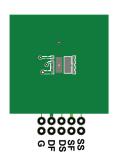
Drair	n-Source Diode Characteristics						
$V_{SD}$	Source-Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.2 A V <sub>GS</sub> = 0 V, I <sub>S</sub> = -1 A	(Note 2) (Note 2)	Q1 Q2	0.8 -0.9	1.3 -1.3	V
t <sub>rr</sub>	Reverse Recovery Time	Q1 I <sub>F</sub> = 6.2 A, di/dt = 100 A/s	(14010-2)	Q1 Q2	69 44	111 71	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$\dot{Q}_{1F}^{Q} = -1 \text{ A, di/dt} = 100 \text{ A/s}$		Q1 Q2	106 68	170 109	nC

**Test Conditions** 

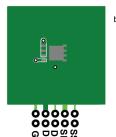
#### Notes:

Symbol

1. R<sub>0.JA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0.CA</sub> is determined by the user's board design.



a.55 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b.55 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper

Type

Min

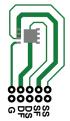
Тур

Max

Units



c. 138 °C/W when mounted on a minimum pad of 2 oz copper



d. 138 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\,\mu s,$  Duty cycle < 2.0%.
- 3. Q1:  $E_{AS}$  of 216 mJ is based on starting  $T_J$  = 25  $^{\circ}$ C, L = 3 mH,  $I_{AS}$  = 12 A,  $V_{DD}$  = 150 V,  $V_{GS}$  = 10 V. 100% test at L = 0.3 mH,  $I_{AS}$  = 28 A. Q2:  $E_{AS}$  of 6 mJ is based on starting  $T_J$  = 25  $^{\circ}$ C, L = 3 mH,  $I_{AS}$  = -2 A,  $V_{DD}$  = -150 V,  $V_{GS}$  = -10 V. 100% test at L = 0.3 mH,  $I_{AS}$  = -6.9 A.
- 4. Pulsed Id please refer to Fig 11 SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

## Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted

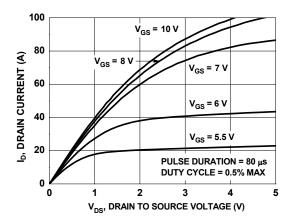


Figure 1. On Region Characteristics

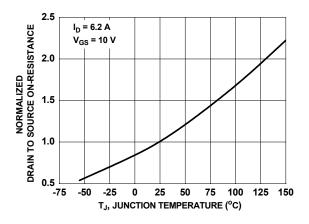


Figure 3. Normalized On Resistance vs Junction Temperature

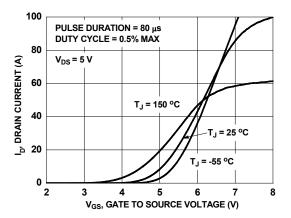


Figure 5. Transfer Characteristics

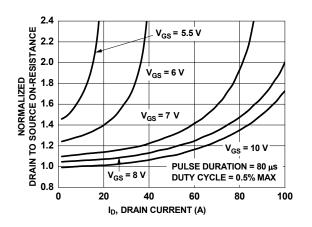


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

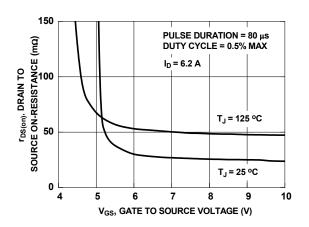


Figure 4. On-Resistance vs Gate to Source Voltage

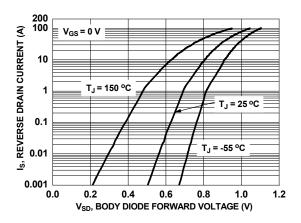


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

#### Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted

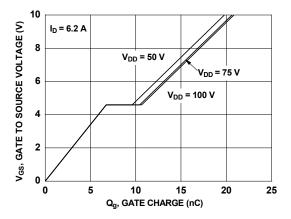


Figure 7. Gate Charge Characteristics

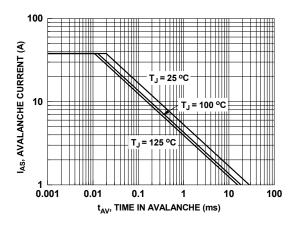


Figure 9. Unclamped Inductive Switching Capability

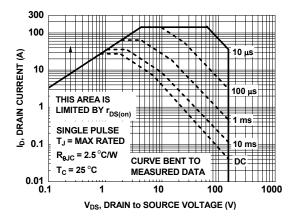


Figure 11. Forward Bias Safe Operating Area

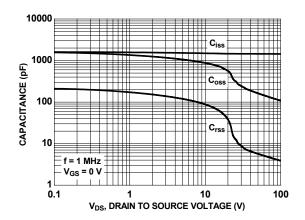


Figure 8. Capacitance vs Drain to Source Voltage

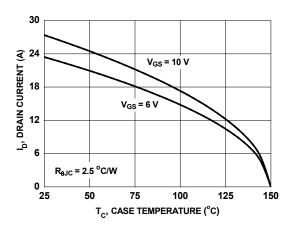


Figure 10. Maximum Continuous Drain Current vs Case Temperature

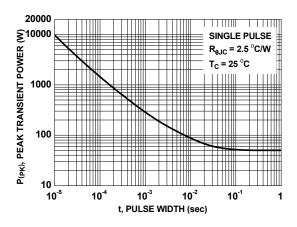


Figure 12. Single Pulse Maximum Power Dissipation

## Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted

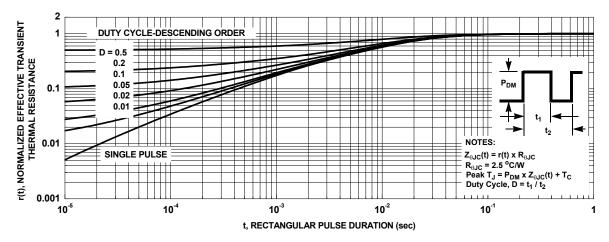


Figure 13. Junction-to-Case Transient Thermal Response Curve

#### Typical Characteristics (Q2 P-Channel) T<sub>J</sub> = 25 °C unless otherwise noted

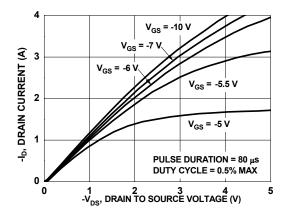


Figure 14. On-Region Characteristics

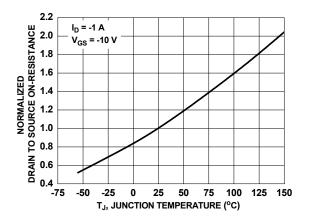


Figure 16. Normalized On-Resistance vs Junction Temperature

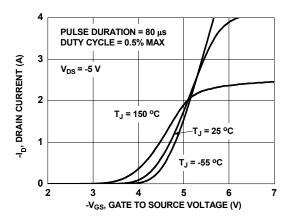


Figure 18. Transfer Characteristics

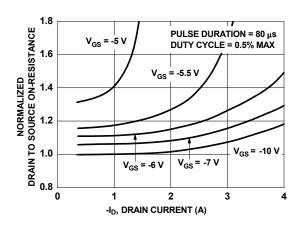


Figure 15. Normalized on-Resistance vs Drain Current and Gate Voltage

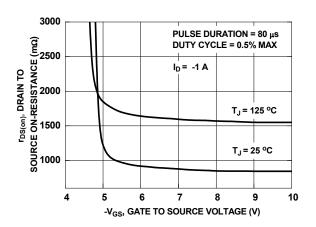


Figure 17. On-Resistance vs Gate to Source Voltage

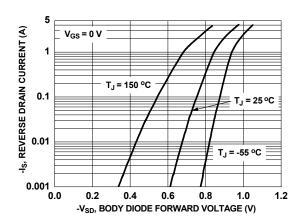


Figure 19. Source to Drain Diode Forward Voltage vs Source Current

7

#### Typical Characteristics (Q2 P-Channel) T<sub>.I</sub> = 25°C unless otherwise noted

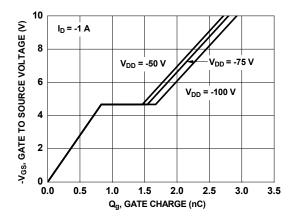


Figure 20. Gate Charge Characteristics

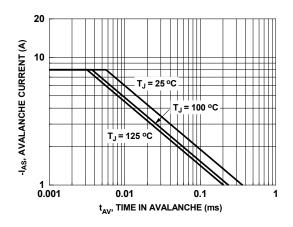


Figure 22. Unclamped Inductive Switching Capability

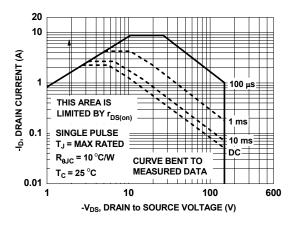


Figure 24. Forward Bias Safe Operating Area

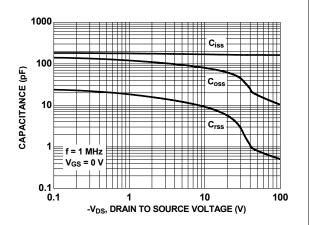


Figure 21. Capacitance vs Drain to Source Voltage

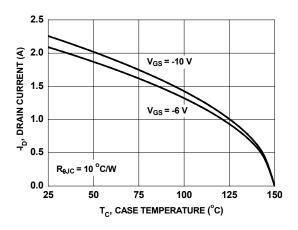


Figure 23. Maximum Continuous Drain Current vs Case Temperature

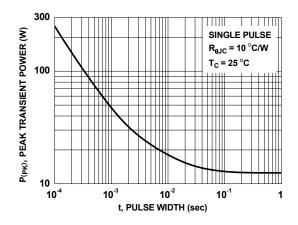


Figure 25. Single Pulse Maximum Power Dissipation

# Typical Characteristics (Q2 P-Channel) T<sub>J</sub> = 25 °C unless otherwise noted

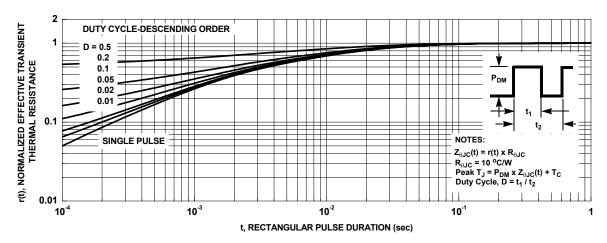
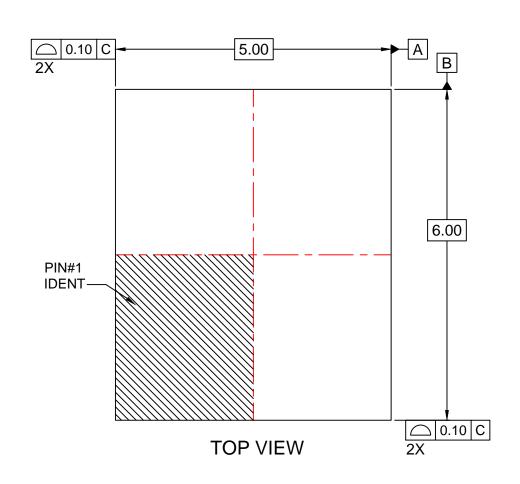
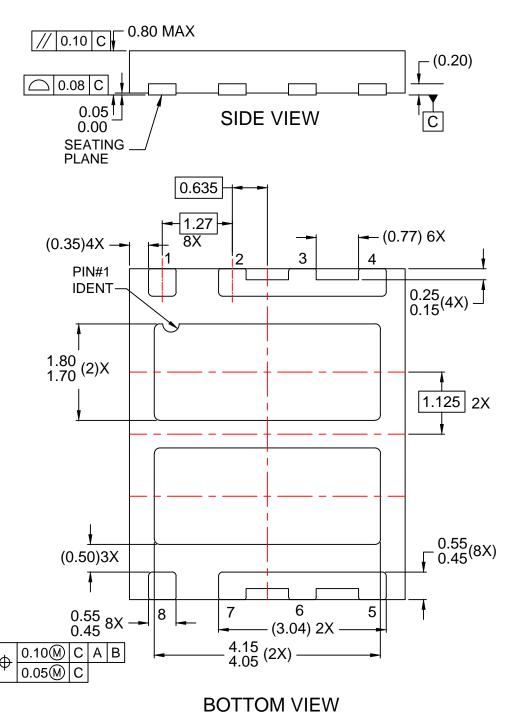


Figure 26. Junction-to-Case Transient Thermal Response Curve





1.75(2X) 1.75(2X) 1.75(2X) 1.75(2X) 0.65(8X) 0.60(8X) 1.27 0.635

**RECOMMENDED LAND PATTERN** 

## NOTES:

- A. DOES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS BASED ON FSC DESIGN ONLY.
- E. DRAWING FILENAME: MKT-MLP08Zrev1.

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